

Design and performance of the ALICE TRD frontend electronics

- Introduction
- Multi Chip Module PASA+TRAP
- Readout tree and GTU
- TRAP and MCM production test
- Conclusions



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TRD Structure





TRD & MCM Functionality

event display for MCM functionality





Transition Radiation Detector

- the TRD is a drift chamber to detect the trajectory of charged particles
- in addition a radiator stack in front to cause transition radiation to separate electrons from pions

Multi Chip Module

- the MCM amplifies and digitizes the analog signals and stores the data
- it performs a line fit and ships the track data off the detector to a global tracking unit
- sends zero-suppressed ADC data after L1A





Line Fit & Global Tracking



tracklet processor

- straight line fit via a linear regression method
- searching for dedicated patterns (for energy cut and electron - pion separation)
- raw data buffer

global tracking

- projection of 'tracklets' to a virtual plane
- searching for tracklets belonging together
- perform cut and generate trigger





Data Flow and Data Reduction





Multi Chip Module





PASA - Preamplifier and Shaper





ADC - Analog to Digital Converter



ADC - Analog to Digital Converter Prof. Tielert, Uni Kaiserslautern

- 10 Bit, 10 MSPS, no latency
- Cyclic ADC, 240 MHz internal
- ◆ ENOB: 9.5
- Power: 10 mW / channel (programmable)
- Area: 0.11 mm² (550 x 200 μm²)







ADC Performance

Sinwave measured using one CPU to copy the ADC data into the memory.

Note that by the normal operation in the detector the ADC data will be processed and stored without turning on the CPUs.











MIMD Processor

MIMD processor Preprocessor, 4 sets of fit data 4 CPUs shared memory / register file global I/O bus arbiter separate instruction memory **IMEM** GRF DMEM coupled data & control paths пп пп **CPU** CPU0 pipeline register decoder CON FIT PRF Harvard style architecture two stage pipeline write back PC select operands interrupt 32 Bit data path register to register operations ALU fast ALU 32x32 multiplication local I/O busses clks ⁴ rst 64/32 radix-4 divider external power maskable interrupts interrupts global I/O bus control I/O bus synchronization mechanisms arbiter





SCSN - Slow Control Serial Network







Readout Tree





NI - Network Interface

♦ I/O interfaces

- direct access via local I/O interfaces
- global I/O configuration and status registers
- ♦ 4 input, 1 output ports
 - •8 Bit data at 120 MHz DDR (240 MB/s)
 - •+ strobe, parity and spare bit
- data resynchronization
- input fifos (256 Bytes / port)
- 1 clock cycle input to output latency incl. data resynchronization

Readout

- collecting data of 65664 MCMs
- interface to the GTU are 1080 optical links with 2.4 GBit/s each
- ♦ readout latency: ~200 ns
- ♦ full trigger readout within 600 ns





Detector Readout









<u>5 mm</u>

OASE - Optical Advanced SErializer Prof. Brüning, Uni Mannheim Prof. Tielert, Uni Kaiserslautern

- ♦ 8 Bit at 120 MHz DDR parallel ↔ 2.4 GBit/s serial tranceiver
- SCSN and I²C configuration interfaces, JTAG
- pins to directly connect laser diodes for on-chip connection



OASE backup solution



Replacement for the OASE board with the same connector and speed

- ♦ 8 Bit at 120 MHz DDR parallel to 16 bit SDR 120 MHz conversion using CPLD
- Commercial gigabit serializer from Texas Instruments
- Driver for the laser diode

Receiver board for testing of the gigabit serializer board

- Amplifier for the photodiode
- Commercial gigabit deserializer from Texas Instruments

The main drawback of this solution is the higher price and the larger number of components





GTU Implementation



Integration prototype







DCS board

Trigger & clock distribution, ARM CPU+FPGA, embedded Linux, Ethernet, serial link to the TRAPs ...





MCM tester

Tests automatically the MCM (TRAP+PASA)

- Power supply control
- Check of the reference voltages
- Charge injection to the PASA inputs
- Digitization of the 3 direct PASA outputs
- Sin-wave to the 3 direct ADC inputs
- Stimuli to all digital inputs, readback of all digital outputs



Automatically positioning by video camera and pattern recognition software Handshaking with the MCM test software Test of 16 MCMs (IPE Karlsruhe)





Wafer tester

Test automatically the TRAP on the wafer:

- The supply currents
- The serial links and pretrigger
- All internal parts using the CPUs
- The parallel output
- The half of the ADCs using a sin wave generator







- A cheap and compact (4x4cm) mixed mode Multi Chip Module was developed, combining charge sensitive preamplifier/shaper, ADCs, digital filters, processors and readout network

- This makes technically possible the required high integration of the front end electronics in order to readout more than million of channels

- The distributed in space digital computing power enables to process such large amount of data in real time

- In addition the high speed low latency readout network and the Global Tracking Unit provide the possibility to use the detector not only for tracking but also for generating L1 trigger in the system

- The building blocks: PASA & TRAP chips and the MCM are produced/partially produced, the test equipments are developed





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THANK YOU

